The 5th IEEE Cyber Science and Technology Congress (CyberSciTech 2020)

The 1st IEEE international workshop on the Impact of Internet of Things on Daily Life (IoT-Life)

June 22-26, 2020, Calgary, Canada

In the recent decade, with the continuing rise of the application of big data in the Internet of things (IoT) in any countries, an unprecedented super-smart society has arrived. There has been an increasing demand on developing daily life supporting services utilizing Internet of things. IoT as an advanced paradigm to connect physical and virtual things for enhanced services, has been introduced that can provide significant improvements in the Improving the convenience of life. Several researches have been devoted to address daily life supporting requirements utilizing IoT-based systems.

This workshop aims to provide a forum for researchers to present thoughts and results for the most recent advances in different aspects of IoT and the supporting of human daily life. We encourage the submission of papers with new theory, analysis, methods, and applications.

TOPICS:

Topics include but are not limited to:

- IoT Architectures, Systems
- IoT Big data, Mobile Services
- IoT Information Management
- Human Behavior Classification and Prediction
- Eye-tracking for data collection
- Motion Capture & Analysis
- Sensors and Smart Objects for Daily Life
- Wireless Sensor Networks for Daily Life
- Data Collection and Analysis for IoT
- Security and Privacy for IoT
- IoT on Smart Education
- IoT on Smart Agriculture
- Intelligence Transportation
- Smart Homes and Smart Cities
- Artificial Intelligence for Health-care
- Medical Applications for IoT
- Block-chain application on daily life



Organising Committee:

Yishui Zhu,

Chang'an University, China

Bo Wu,

Waseda University, Japan

Hong Chen,

Daiichi Institute of Technology, Japan

Important Dates:

Submission Due: March 10, 2020 Authors Notification: April 1, 2020 Camera-ready: May 10, 2020

Submission:

All accepted papers will be published by IEEE in Conference Proceedings (IEEE-DL and EI indexed).

Link





